



Attorney Docket No. 0756-7275

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Hidekazu MIYAIRI et al.

Serial No. 10/808,499

Filed: March 25, 2004

For: METHOD FOR TESTING

SEMICONDUCTOR FILM,

SEMICONDUCTOR DEVICE AND

MANUFACTURING METHOD

THEREOF

) Group Art Unit: 2857

) Examiner: Jeffrey R. West

) CERTIFICATE OF MAILING

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) Adrian M. Stamps

)

)

AMENDMENT

Honorable Commissioner of Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

In response to the Official Action dated January 26, 2006, please consider the following amendments and remarks in connection with the above-identified application.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 5 of this paper.

Amendments to the Drawings begin on page 15 of this paper and include an attached replacement sheet.

Remarks begin on page 16 of this paper.